



CALL FOR PAPERS

The IEEE European Test Symposium (ETS) is Europe's premier forum dedicated to presenting and discussing scientific results, emerging ideas, hot topics, and new trends, industrial case-studies and applications, in the area of electronic-based circuits and system testing, reliability, safety, security and validation. The 2021 edition of ETS will be a virtual one. The organizing team will strive to keep the spirit of ETS alive, by organizing an event with live sessions and many opportunities for networking and peer interaction. ETS'21 is organized jointly by KU Leuven and imec, which co-sponsor the event together with the IEEE Council on Electronic Design Automation (CEDA).

The program includes keynotes, scientific paper presentations, panels, tutorials, workshops and highlights/demos from industry. Besides regular technical papers, ETS'21 provides the opportunity of submitting scientific contributions for hot-topic papers and case-study papers (each with specific evaluation criteria). Submissions are also solicited for special sessions, panels, tutorials and workshops, as well as for the PhD Forum. Linked to the main ETS'21 symposium, the Test Spring School and Fringe Workshops will be organized.

You are invited to participate and submit your contributions to ETS'21. The areas of interest include (but are not limited to) the following topics:

3D IC and SiP Test	Heterogeneous and Emerging Architectures
Analog, Mixed-Signal and RF Test	High-Speed I/O Test
Approximate Circuit Testing	IoT and CPS Dependability
ATE Hardware and Software	Low-Power Test

Automatic Test Generation	Machine Learning and Test
Automotive and Avionics Test	Memory Test and Repair
Board Test and Diagnosis	Microsystems / MEMS / Sensors Test
Built-In Self-Test	On-line Test
Current-Based Test	Power- / Thermal-Aware Test
Defect-Based Test	Processor Test (Multi-Core, GPU, CPU, Neuromorphic, etc.)
Delay and Performance Test	Security-Test Trade-offs
Design for Test	Self-X (Awareness, Repair, Test, etc.)
DfX (Design for Manufacturing, Reliability, Yield, etc.)	Signal Integrity Test
Diagnosis and Silicon Debug	SoC and NoC Test
Economics of Test	Standards in Test
Extra-Functional Aspects	Test for Reversible and Quantum Circuits
Failure Analysis	Test of Reconfigurable Systems (FPGA, CPLD, etc.)
Fault Modeling	Test, Reliability and Security of Emerging Technologies
Fault Simulation	Trojan Detection
Fault Tolerance	Verification and Validation
Functional Safety	Yield Analysis and Enhancement
Hardware Security	

Publications

ETS'21 will produce Formal Proceedings of scientific papers with ISBN number that will be indexed by the IEEE Xplore Digital Library. All accepted technical papers submitted in one of the three categories (regular, hot topic, and case study) will be included in the formal Proceedings (each following its own guidelines). Extended versions of selected papers will be invited for submission in an IEEE Journal Special Issue dedicated to ETS'21.

Submissions

- **Scientific papers** for the Formal Proceedings:
 - **Regular Papers**, presenting novel and complete research work;
 - **Hot-Topic Papers**, presenting early innovative ideas with in-progress results, emerging and future test/reliability/safety problems, or identifying open problems that merit innovative future research;
 - **Case-Study Papers**, presenting relevant industrial (or industrial collaboration) data that demonstrate a previously published concept, or that can help further research advancements.
- **PhD Forum Contributions** from students eager to discuss their on-going research.
- **Proposals for Panels, Embedded Tutorials, Special Sessions and Fringe Workshops.**
- **Industrial Presentations and Table-top Demos** focusing on new features of test/reliability/safety- related products.

Key Dates for Submissions

Submission deadline for scientific papers: **December 17th, 2020**

Submission deadline for PhD Forum, panels, embedded tutorials, special sessions and fringe workshops: **January 22nd, 2021**

Notification of acceptance: **February 12th, 2021**

Camera-ready manuscript and author registration: **March 15th, 2021**

A PDF version of this CfP can be found [here](#).